

## AMENDMENTS TO THE CLAIMS

This listing of the claims will replace all previous versions thereof.

1. (Currently Amended) A method of inspecting a workpiece, comprising ~~the acts of:~~  
~~providing the workpiece; projecting~~ generating an array of charged particle beams ~~towards the~~  
~~workpiece~~; passing each of the charged particle beams through one of a plurality of pole pieces,  
there being one pole piece associated with each charged particle beam, and through a single lens  
coil surrounding the plurality of pole pieces; directing the array of charged particle beams onto a  
area of the workpiece so as to produce secondary or backscattered particles; detecting ~~resulting~~  
~~the~~ secondary or backscattered particles ~~from the workpiece~~; and ~~determining a presence or~~  
~~absence of defects in the workpiece from the detected particles~~ reconstructing an image of the  
area of the workpiece from detected ones of the secondary or backscattered particles.

2. (Original) The method of claim 1, wherein each of the charged particle beams is  
directed onto a different region of the workpiece.

3. (Currently Amended) The method of claim 1, further comprising ~~the act of~~ translating  
the workpiece relative to an axis of the array of charged particle beams.

4. (Currently Amended) The method of claim 1, further comprising ~~the acts of:~~  
determining if one of the charged particle beams has failed; and translating the workpiece  
relative to the array of charged particle beams, thereby to direct ~~one of the~~ a remaining one of the  
charged particle beams onto that portion of the workpiece onto which the failed beam was  
intended to be incident.

5. (Currently Amended) The method of claim 1, further comprising ~~the acts of~~ focusing individually each of the charged particle beams onto the workpiece; and providing a plurality of additional focusing fields, one associated with each of the beams.

6. (Currently Amended) The method of claim 5, wherein the additional ~~focussing~~ focusing fields are located at a perimeter of the array of charged particle beams.